

Deep learning with LPC and wavelet algorithms for driving fault diagnosis

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Sensors (Basel)

2022; 22(18):e7072

ARTICLE IDENTIFIERS

DOI: 10.3390/s22187072

PMID: 36146421

PMCID: not available

JOURNAL IDENTIFIERS

LCCN: 2002242115

pISSN: not available

eISSN: 1424-8220

OCLC ID: 47250782

CONS ID: not available

US National Library of Medicine ID: 101204366

This article was identified from a query of the SafetyLit database.